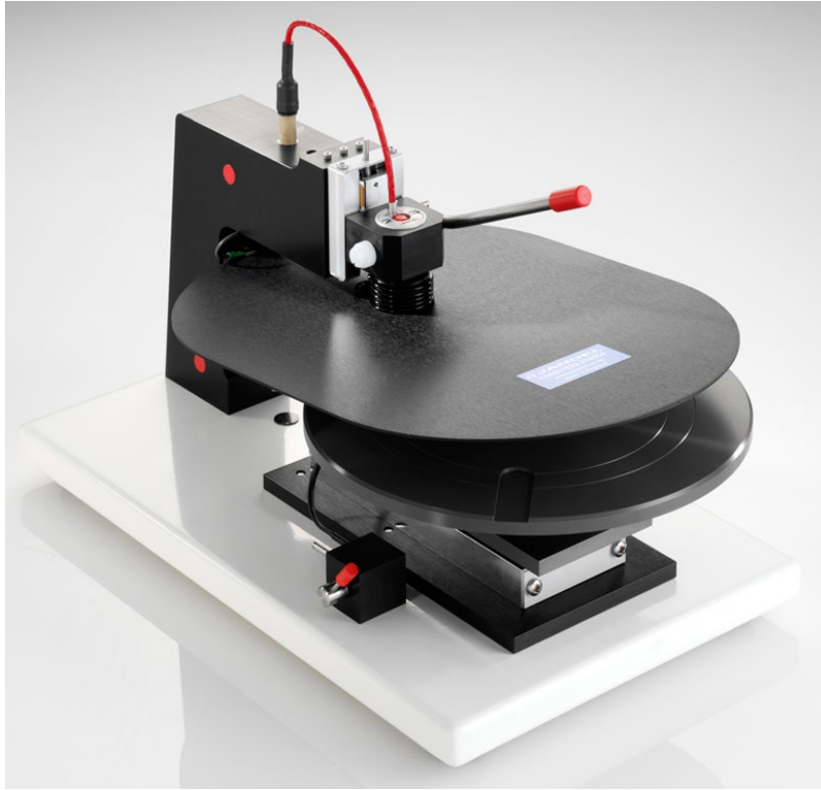


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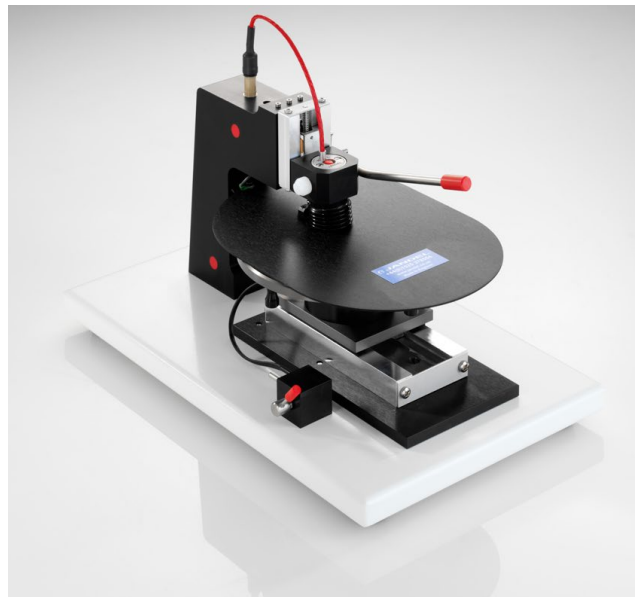


Jandel Multiposition Probe stand

Jandel Engineering Limited offers the Multiposition Probe stand as a solution for measurements on wafers up to 200mm diameter. The probe is available in two sizes at the same cost. One size is for wafers up to 150mm diameter and the second for wafers up to 200mm diameter. If small sized wafers are to be measured, the smaller version is more suitable for placement of the wafers on the measurement table. The Θ movement clicks in four positions at 90 degrees and the linear movement in up to 10 positions. These two factors give repeat placement accuracy of +/- 1mm.

Max. sample size	150mm wafer (200mm wafer on request at no extra cost)
Max. sample thickness	Samples up to 4mm thick can be measured
Microswitch	Prevents current flow when probe is not in contact with sample
Manual control	Simple lever operation for probe contact and removal
Simple set up	Single wire connects probe stand and measurement electronics
X - Θ stage	Repositioning accuracy of +/- 1mm

Note: Our Multiposition Probe stand includes a cylindrical four point probe head. For more information on cylindrical probe heads and the specifications available, please see our cylindrical probe head datasheet.



If you require any further information on the Jandel Multiposition Probe stand, please do not hesitate to contact us using the details below.